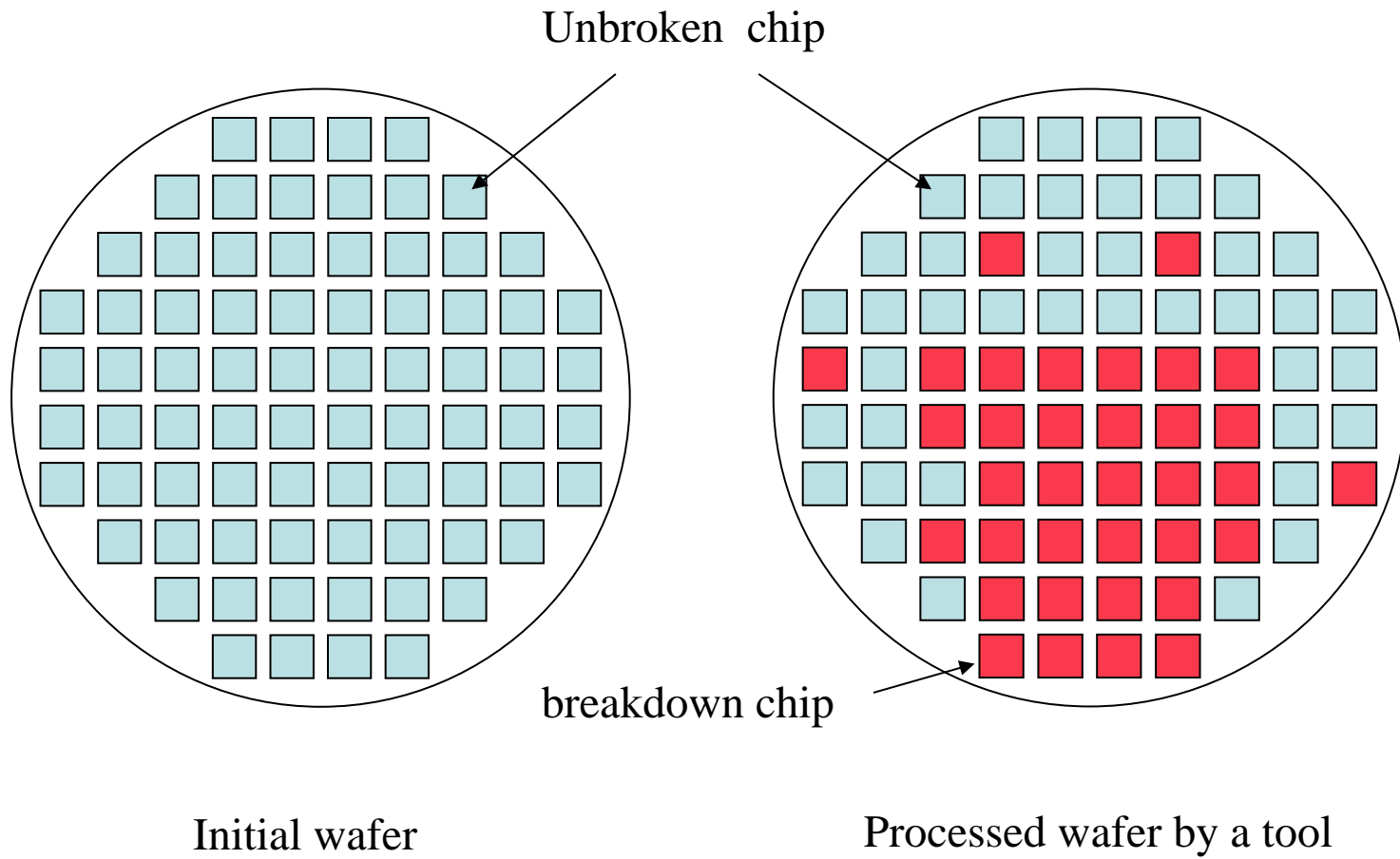


**Charge-up damage Monitor TEG  
for Process Yield Security**

**YST**

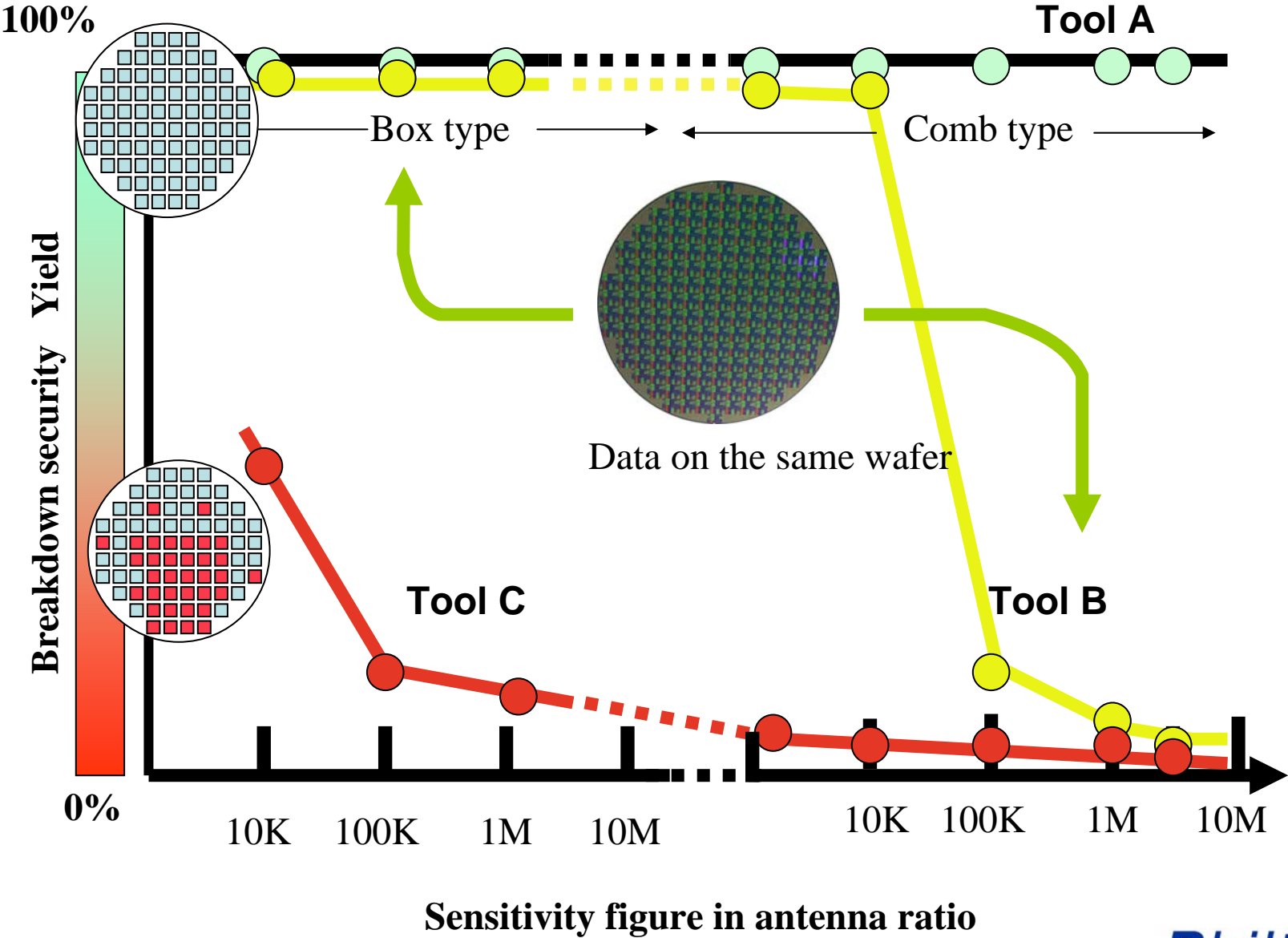
*Philtech Inc.*

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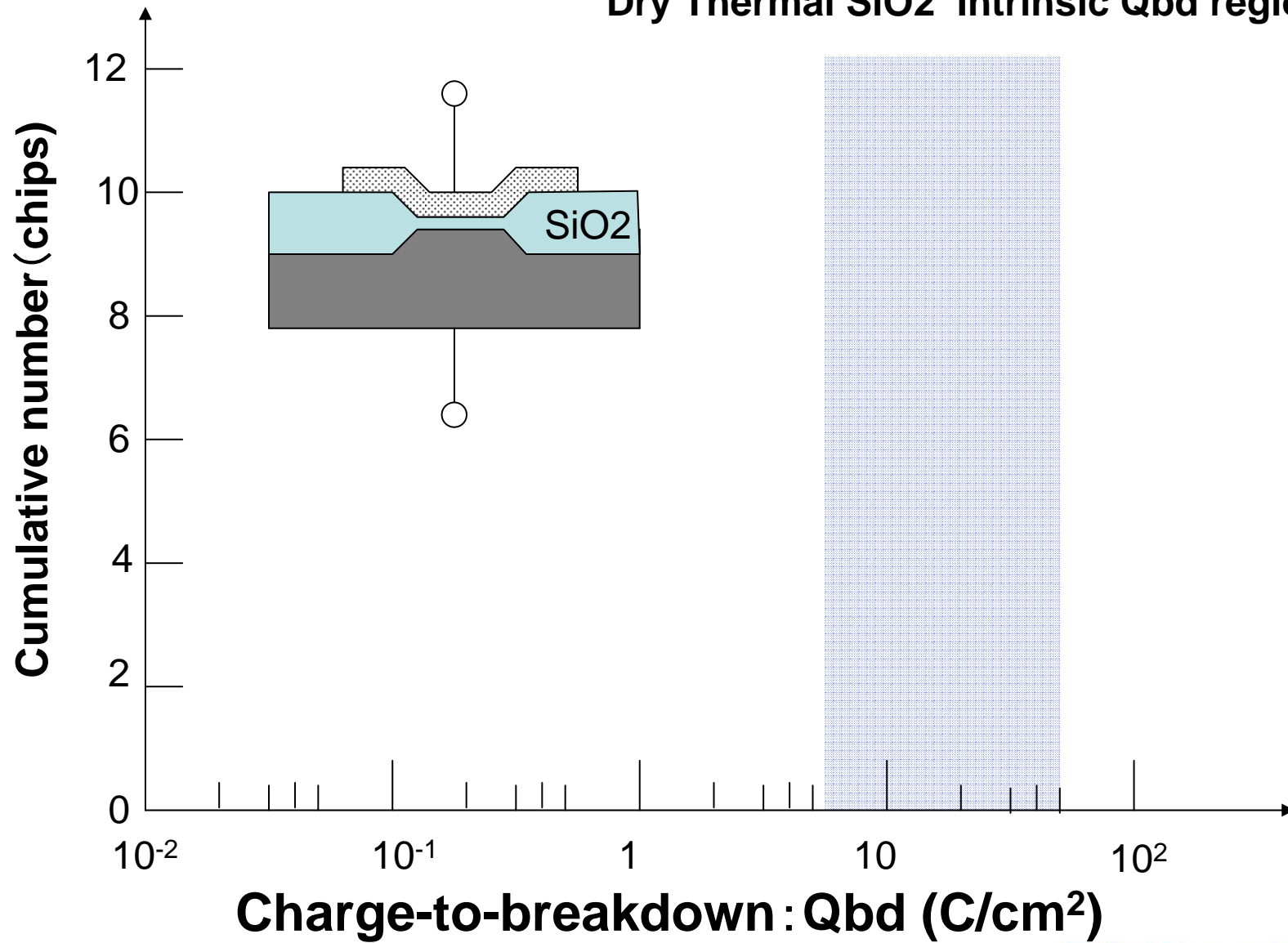


Service by YST: breakdown chip map

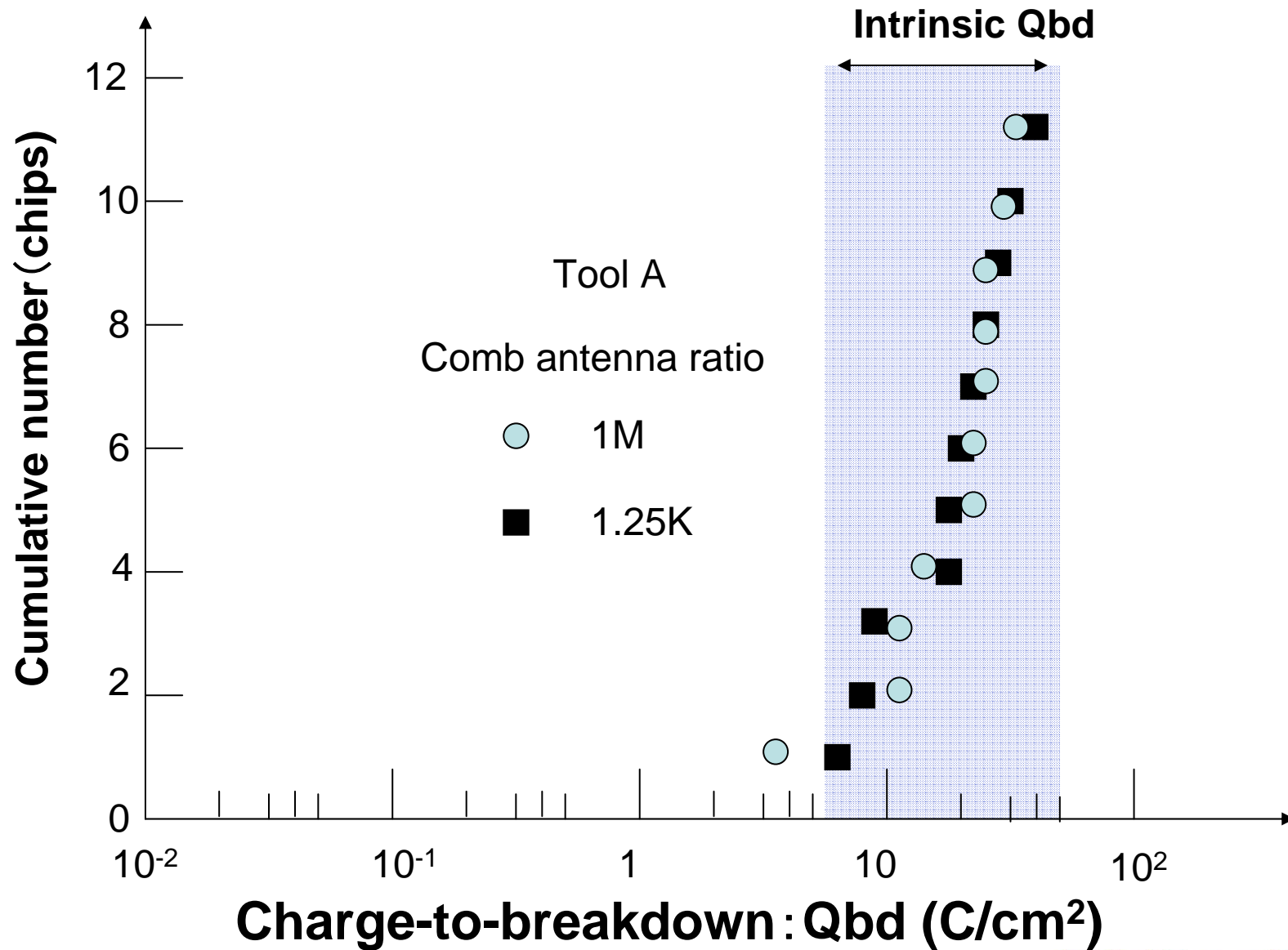
# Breakdown security yield model

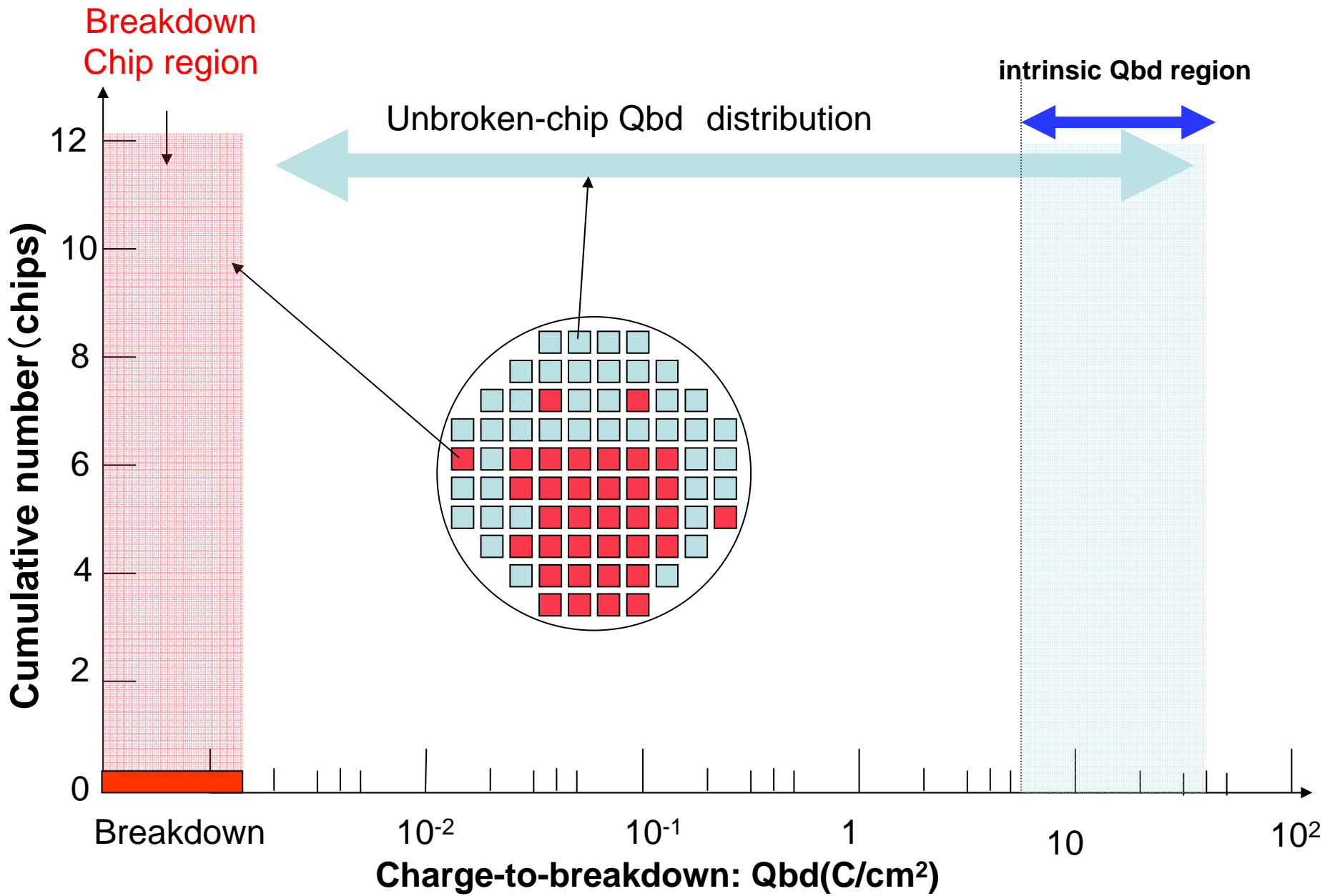


### Dry Thermal SiO2 Intrinsic Qbd region

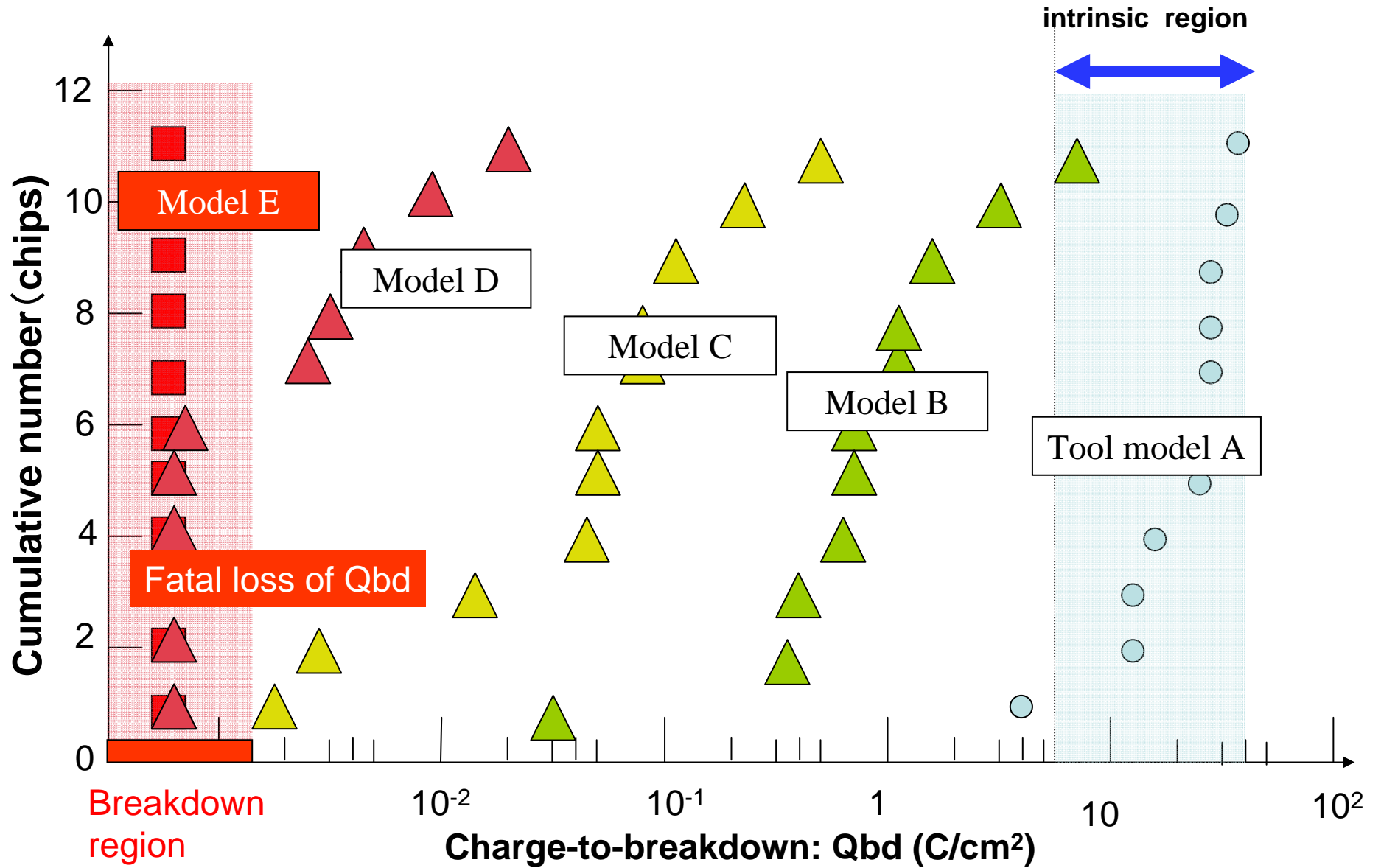


# Service by YST: Measured Qbd as a damage figure

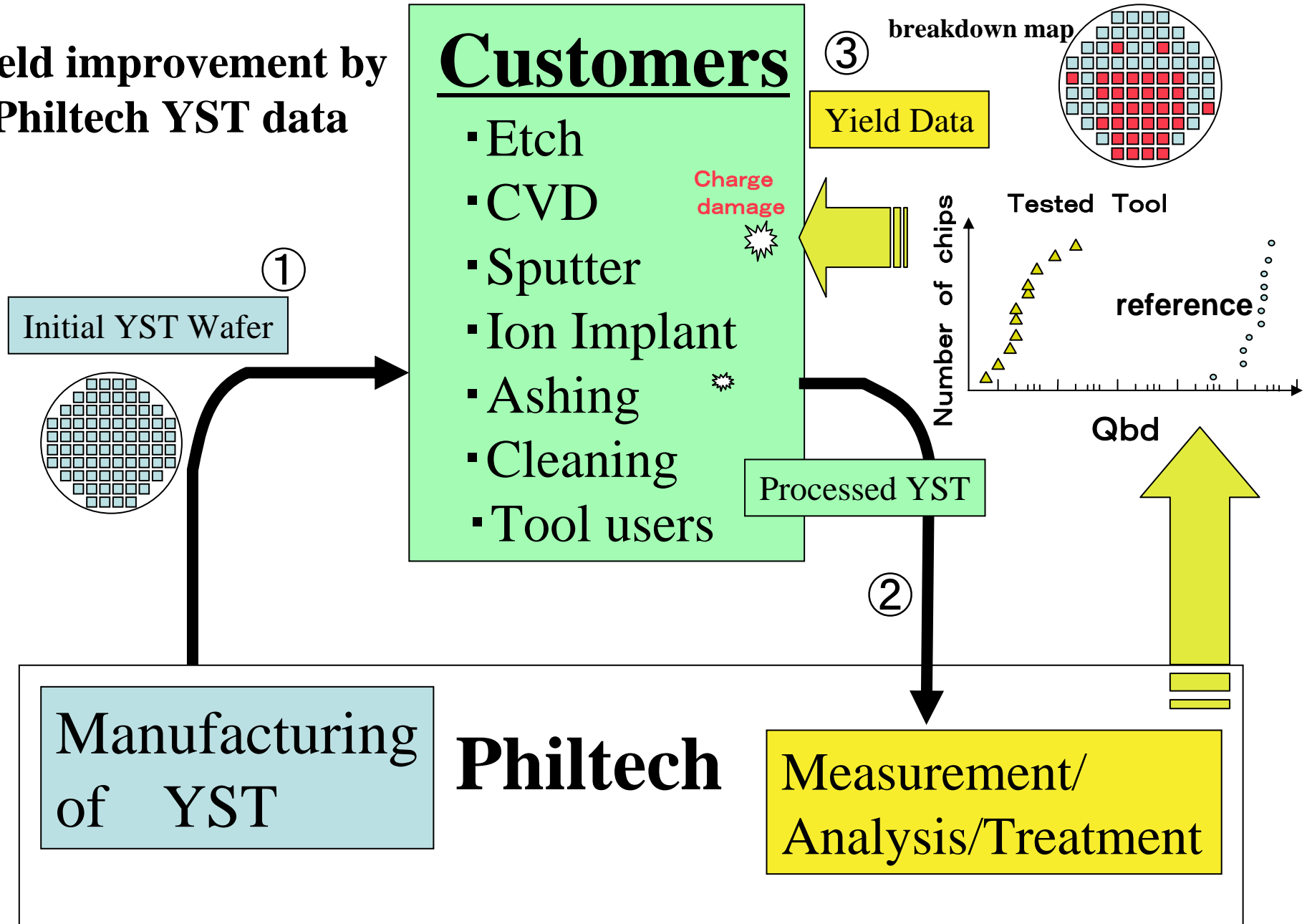




# Qbd loss as a damage figure by Philtech 300mm YST



# Yield improvement by Philtech YST data



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